12. (New) The tip as recited in claim 11, wherein said tip includes a dielectric band.

13. (New) A thermokeratoplastic probe that can be used to denature a cornea, comprising:

a handle;

a first connector attached to said handle;

a second connector that mates with said first connector; and,

a tip that is coupled to said second connector, said tip having a length between 300 and 600 microns.

14. (New) The ~~thermokeratoplastic~~ thermokeratoplasty probe as recited in claim ~~13~~ 2, further comprising a stop that limits an insertion depth of said tip into the cornea.

15. (New) The thermokeratoplastic probe as recited in claim 13, wherein said tip is located at a distal end of a spring beam.

16. (New) A thermokeratoplastic system for denaturing a cornea, comprising:

a thermokeratoplastic probe which has a tip that can be placed in contact with the cornea; and,

a power supply which provides no more than 1.2 watts of power to said thermokeratoplastic probe for a time duration no greater than 1 second.

17. (New) The system as recited in claim 16, further comprising a ground pad that provides a return path for the power provided to said thermokeratoplastic probe.

18. (New) The system as recited in claim 16, wherein said ~~thermokeratoplastic~~ probe includes a tip which has a length between 300 and 600 microns.

19. (New) The system as recited in claim 16, wherein said ~~thermokeratoplastic~~ thermokeratoplasty probe includes a handle, a first connector attached to said handle, and a second connector that mates with said first connector.

20. (New) The system as recited in claim 18, wherein said ~~thermokeratoplastic~~ thermokeratoplasty probe includes a stop that limits an insertion depth of said tip into the cornea.

21. (New) The system as recited in claim 18, wherein said tip is located at a distal end of a spring beam.